Special Issue

Metrology in Manufacturing

Message from the Guest Editors

Metrology, the science of measurement, is undergoing significant development in the light of new challenges of precision manufacturing and digital transformation. Recent developments in complex products, novel materials, advanced manufacturing processes, and enhanced measurement systems lead to new challenges for metrology in manufacturing. This special issue aims to present some of the recent research in manufacturing metrology covering both fundamental research and applications. We welcome state-of-the-art reviews, cross-disciplinary research fronts and industrial applications to highlight the current advancements in manufacturing metrology. Keywords

- In situ, in-process, and in-line measurements
- Advanced coordinate measuring systems
- Machine-tool metrology
- Robotic measurement and inspection
- Optical systems in dimensional metrology
- Computed tomography in dimensional metrology
- Multisensor measurement in dimensional metrology
- Cloud of points and geometry processing in dimensional metrology
- Metrology for additive manufacturing
- Metrology for process control and optimization
- Metrology systems and Industry 4.0
- Training and education aspects

Guest Editors

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Prof. Dr. Edward Morse

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Deadline for manuscript submissions

closed (30 September 2021)

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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